

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243057US2SRD		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Munehiro OGASAWARA					
		FILING DATE Herewith				GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
<i>QZ</i>	AO	7-61185	03/20/95	JAPAN			X
<i>QZ</i>	AP	2001-34115	02/09/2001	JAPAN			X
<i>QZ</i>	AQ	2001-217173	08/10/2001	JAPAN			X
<i>QZ</i>	AR	9-289164	11/04/97	JAPAN			X
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>QZ</i>	AW	N. SHIMOMURA, et al., "OPTICAL COLUMN OF THEMASK-SCAN EB MASK WRITER TEST STAND", Vol. 4066, pgs. 605-612, SPIE, 2000					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>QZ</i>				Date Considered <i>6/12/04</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							